# 國立中正大學

### 資訊工程研究所碩士論文

40 奈米製程下開發與設計快速鎖定之 全數位鎖相迴路

# Design of A Fast Lock-in All-Digital Phase-Locked Loop in 40-nm CMOS Technology

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### 研究生 羅啟光 所提之論文

<u>40 奈米製程下開發與設計快速鎖定之全數位鎖相迴路 Design of A</u> <u>Fast Lock-In All-Digital Phase-Locked Loop in 40-nm CMOS technology</u> 經本委員會審查,符合碩士學位論文標準。







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### 摘要

近年來,系統晶片(SoC)被廣泛的應用在生醫電子、展頻電路、植入式醫療裝置以及無線網路等應用,由於在 SoC 中,需要供應不同頻率的工作時脈到 不同 I/O 介面,因此,鎖相迴路(PLLs)經常使用在 SoC 上,以產生多組不同的 工作時脈。此外,這些應用的需求在於低耗能及低成本。

隨著先進 CMOS 製程的開發,工作電壓不斷的下降,傳統 PLL 在設計上 遭遇很大的挑戰。基於 time to market 的考量,為了減少重新設計 PLL 的時間 與努力,ADPLL 採用了全數位的設計方式,以及使用標準元件(Standard Cell) 實現 ADPLL,不僅加速了設計過程,更增加 PLL 的移植性,相較於傳統 PLL, 全數位鎖相迴路(ADPLL)更適合用於 SoC 上。

由於傳統 PLL 的鎖定時間都很長,導致 PLL 需要較長的工作時間。當系統待命時,PLL 的耗能即成為 SoC 待機(Standby)時功率消耗的主要來源。因此, 若縮短 PLL 的鎖定時間,即早鎖定頻率及相位,PLL 便可隨需求關閉以減少耗 能,快速鎖定的 ADPLL 變成設計的趨勢。

因此,在本文中,我們提出快速鎖定的全數位鎖相迴路,透過校正及補償 機制來降低面積成本的消耗,以及提升鎖定中心頻率的精準度,是本論文的主 要目的及貢獻。本論文以 40 奈米製程標準元件庫實現,並驗證我們所提出的 電路架構。

**關鍵字:**全數位鎖相迴路、快速鎖定全數位鎖相迴路

### Abstract

In recent years, biomedical electronic applications, spread-spectrum clock generators, implantable medical devices, and frequency hopping wireless applications are widely used in system-on-a-chip (SoC). In an SoC, it requires different clock sources for different I/O interfaces. Thus, phase-locked loops play an important role in SoC in order to generate different clock sources. Besides, the primary concern of these applications are low energy and low cost.

While the operation voltage is scaling down with the latest CMOS process, analog PLLs encounter great design challenges. According to time to market, in order to minimize the design time and the design efforts, all-digital phase-locked loops (ADPLLs) are adopted in digital design approaches. In addition, ADPLLs implemented with standard cells can not only speed up the design time, but also improve the portability. As compared with analog PLLs, ADPLLs are more suitable for SoC.

Analog PLLs are usually not to be stopped due to the long lock-in time. When the system is in sleeping mode, the PLL power consumption dominates the standby power consumption of the system. Therefore, if PLLs can lock the frequency and phase quickly, the lock-in time can be reduced so that PLLs can be turned off in low power modes. As a result, fast lock-in ADPLLs become more and more popular.

Therefore, in this thesis, we proposed a fast lock-in ADPLL with a calibration method in order to decrease the chip area and improve the accuracy in frequency estimation. In addition, the test chip is implemented and verified in TSMC 40-nm CMOS process with standard cells.

# Keywords : All-Digital Phase-Locked Loop (ADPLL), Fast Lock-in ADPLL - III -



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## Chapter 1

# Introduction

### 1.1 Why the Feature of Fast Lock-in is

### **Required in ADPLL**

In recent years, phase-locked loop (PLL) plays an important role in system-on-chip (SoC). In an SoC, it usually requires several PLLs to provide different clock sources for different I/O interfaces. PLLs generate various frequencies to apply to different applications and it is widely used in mobile communication system, wireless communication system and biomedical electronic.

Traditionally, PLL is implemented by a charge-pump phase-locked loop which faces design challenge of leakage current in advanced CMOS process. Besides, the gain of voltage controlled oscillator ( $K_{VCO}$ ) becomes larger due to the narrower range of the control voltage. Thus it easily suffers from noise on the control voltage. Traditional PLLs contain some passive components to design an analog loop filter that occupies huge chip area and has higher chip cost. Traditional PLLs also have a long lock-in time and have high power consumption. Therefore, in the era of the nano-scale process, PLLs which consist of a VCO, a charge-pump and an analog loop filter are not suitable for SoC that demands low power, low voltage operation, low chip area and especially requires fast locking [18].



Fig. 1.1: ADPLL Architecture.

An all-digital phase-locked loop (ADPLL) takes the advantages of CMOS process as shown in Fig. 1.1. Compared with the traditional PLL, the ADPLL replaces passive components with the digital circuits, a VCO to a digital-controlled oscillator (DCO), and an analog filter to a digital filter. The chip size is reduced and the chip cost decreased accordingly. As a result, an ADPLL can operate at low voltage and have low chip area due to all digital design techniques.

The evolution of traditional PLLs into digital PLLs, some issues need to conquer such as the efficacy of the DCO. A DCO occupies about half of the PLL area and also consumes most portions of the power of the ADPLL. Therefore, DCO is the most critical component in an ADPLL. In [21], it presents a smooth code jumping technique to reduce output jitter. However it requires two DCOs for comparison and costs huge area. Moreover, there are some papers research on a wide-range, high resolution and monotonic DCO. In [22], a DCO architecture that can be glitch free is presented.

In [23], an interpolating DCO is proposed to improve the architecture of DCO. The sequential bandwidth needs to overlap in order to prevent from the PVT variation. However, the performance of the DCO [23] becomes worse as operating at high frequency, the differential nonlinearity (DNL) is higher than 0.4 LSB. A wide frequency range and low supply sensitivity DCO is proposed in [24], it tunes the transistor sizes in order to compensate the delay variation of delay line due to voltage variations. However, migrating to another CMOS process or with the DC voltage drop, the size of the transistors required to be retuned. In [20], a monotonic DCO with the calibration circuit achieves low power consumption and low jitter performance. As a result, DCOs can reach low power [33], low jitter, fine resolution [18], and wide frequency range [23] that is more suitable than traditional PLLs in SoC applications.

In wire and wireless applications, digital PLLs become popular due to the process scaling down. In [1], a fast-lock digital PLL with a LC DCO that generates eight phase. The LC DCO operates at high frequency and generates a stable clock to the system. However, the LC DCO demands for large area. In order to reduce chip area and device noise, [28] proposes three TDCs and a DCO to replace the LC structure. Although three TDCs and a DCO successfully decrease the chip area, three TDCs encounter the PVT variation that causes poor linearity. On the other hand, [28] abandons the architecture of LC DCO, while operating at high frequency, the device noise must worse than the LC DCO. As a result, wire and wireless application requires for high frequency, ADPLL with LC DCO meets the requirement and provides stable signal to the system.

Furthermore, injection-locked [35]-[39] has been used in PLLs recently to improve the jitter and phase noise. The primary premise of injection-locked PLL is the feedback clock should be continuously output and closes to the reference clock. Therefore, injection-locked PLLs require addition calibration process to make sure the feedback clock is in the locking window with the PVT variation. If the feedback clock exceeds the locking window, the injection-locked PLL will be failed. For instance, in [39], the locking window is designed less than 1MHz. However, injection-locked transfers from VCO to DCO, in [37]-[39], these papers exploit DACs or varactors to achieve digital controlled. As a result, ADPLL based on injection-locked attains low jitter, low power and small area. However the limitation is the narrow locking window. According to  $P = CV^2 f$ , reducing the operation supply voltage is an efficient approach to minimize the dynamic power consumption. However, scaling down the operation supply voltage causes design challenges in traditional PLLs. ADPLLs can conquer this situation and work at low supply voltage to achieve the low power consumption [10] [25]-[27] [40]. In [25], an ADPLL with a digital supply regulator (DSR) increases the DCO supply voltage so that the DCO can operate at a higher supply voltage than reference voltage. However, the DSR consumes almost half of the power of overall and occupies lots of chip area.

In [26], a DCO is designed which not runs at full swing so that can minimize the power consumption. Although it can operate at 0.5V supply voltage and optimizes the power consumption, it has poor jitter performance and costs extra chip area. Furthermore, [27] proposes a customized set-reset latch (SR-Latch) that can survive in 0.25V supply voltage and latches the value. However, it is not able to dynamically adjust the multiplication factor and the sub frequency bands of the DCO require being overlapped to overcome the PVT variations. Besides, the lock-in time is increased due to the low supply voltage. In [10], it provides a pulse latch DFF which can operates at low supply voltage and the ADPLL also achieves fast lock-in time. For time to market, an ADPLL is more suitable in SoC design.

Fast lock-in ADPLLs [10] [11] [13] [18] [19] and [29] are widely used in biomedical electronic applications, frequency hopping wireless applications, spread-spectrum clock generators, grid applications, and implantable medical devices. These applications require reducing the standby power consumption and switch to different frequency channels as fast as they can. If an ADPLL has a fast lock-in time, when high-speed clock generation is not required, the ADPLL can be turned off into sleep mode in order to minimize the power consumption. Thus, fast lock-in ADPLLs are important to meet the low-power demand.

### **1.2 Conventional Fast Lock-in Methods**

### Survey

### **1.2.1 Binary Search Algorithm**

The binary search algorithm (BSA) is a well-known approach used in tracking frequency and phase in [15], [16], [19] and [34], for frequency and phase tracking process. As searching for the target frequency, the search step is arranged in descending order. In [19], after the system reset, the PFD starts detecting the phase and frequency error between the reference clock and the feedback clock. Then, the PFD outputs leads or lags to the ADPLL controller which determines the DCO should speed up or slow down. While the output of the PFD changes from leads to lags (or lags to leads), the polarity is triggered and the frequency gain is divided by two repeatedly until the frequency gain is reduced to the minimum value. In the end, the target frequency is acquired as shown in Fig. 1.2.



Fig. 1.2: Binary Search Algorithm.

In [15], a frequency comparator which has two frequency gains for adding or subtracting is presented. The frequency comparator detects the relative frequency of the reference clock and the DCO clock, then the frequency comparator outputs fast signal or slow signal that depends on the DCO clock is faster or slower than the reference clock. While the comparator output changes from fast signals to slow signals, the algorithm reduces to a quarter of the frequency gain.

For example, in table 1.1 we initialize the DCO control code at 640; the add gain at 640; the sub gain at 320. In the first cycle, the comparator outputs a slow signal so that the DCO control code adds the value from the add gain to speed up the DCO. Then, the comparator outputs the fast signal, thus the DCO control code is subtracted the value from the sub gain to 960 and the add gain is divided by four to 160. While the slow signal consecutive occurs, the DCO control code is added by the value of the add gain twice and so on. Therefore, when the fast signal and a slow signal are interchanged, it divides the frequency gain value by four. Otherwise, the frequency gain value is preserved and the ADPLL controller keeps tracking the frequency.

Frequency Compare	Initial	slow	Fast	slow	slow	fast
Add Gain	640	640	160	160	160	40
Sub Gain	320	320	320	80	80	80
DCO Control Code	640	1280	960	1120	1280	1200

Table 1.1: An Example of Binary Search Algorithm in [15].

In [16], a modified binary search algorithm is shown in Fig. 1.3. While the PFD output changes from lead to lag (or lag to lead), the modified binary search algorithm records the control code and jumps to a calculated code which is the averaged value of the last record DCO control code and the current DCO control code. Therefore, the modified binary search algorithm not only reduces the lock-in time, but also stabilizes the frequency during the frequency tracking.



Fig. 1.3: Modified Binary Search Algorithm.

The binary search algorithm is intuitional and has low design complexity. However, it still spends a lot of time in obtaining the target frequency. The initial DCO control code is tricky, if the initial control code is closed to the target frequency, the ADPLL lock-in time can be significant reduced. However we are not able to find the target DCO control code at the beginning. If the initial code is set to the target control code, the output frequency of the ADPLL will be far from the target frequency due to the large gain at first. In addition, the binary search algorithm takes several cycles to relock the frequency. Consequently, the binary search algorithm is not suit for fast lock-in ADPLLs owning to a long lock-in time.

#### **1.2.2 Gear Shifting**

The gear-shifting algorithm is proposed in [7], [8] and [30]. The gear-shifting algorithm changes the bandwidth in different modes in order to acquire the target frequency fast and reduce the phase noise.



The modes of the gear-shifting algorithm are shown in Fig. 1.4. Three DCO banks are switched during the frequency locking. The PVT-calibration mode is used to calibrate the DCO center frequency. As tracking the target frequency, the loop bandwidth is wide to achieve fast lock-in. In [7], it sets the frequency search step to 460 KHz to speed up the PLL in the acquisition mode. The wide bandwidth results in large phase noise. During the phase tracking mode, the gear-shifting algorithm uses a narrower bandwidth to reduce the phase noise and spur after the acquisition mode.



Fig. 1.5: Block Diagram of the Loop Filter.

The digital loop filter is shown in Fig. 1.5, two paths a proportional path and an integration path are changing during the frequency tracking. The proportional path is changed with the current output of the phase frequency detector (PFD); the integration path is accumulated by the history of the PFD output. Each output from the PFD is added in the proportional path to control the DCO. At the same time the integration path is accumulated the phase error. While in different modes, the integration path provides different amount of phase error integration results. As the PLL in the acquisition mode, the proportional path is selected to acquire the target frequency as fast as it can. As the PLL in the tracking mode, the integration path is selected to reduce the control code variations and to stabilize the DCO. At last, the loop filter feds the controlled code to the DCO by adjusting weighting ratios between the proportional path and integration path to achieve fast lock-in.

However, the gear-shifting algorithm [7] uses a narrow bandwidth to stabilize the DCO, it cost less than 50µs (650 reference cycles) to achieve lock-in. Furthermore, the weighting ratios of the integration path and the proportional path are a tradeoff between the lock-in time and the phase noise. As migrating to different CMOS

process, the value in the loop filter may be different to achieve fast lock-in. Therefore, the gear-shifting algorithm requires to resimulate in different process.

In [8], a modified bang-bang algorithm which is similar to gear-shifting algorithm is presented. If the PFD outputs n consecutive leadings or laggings, the proportional path of the loop filter outputs  $\beta \times n$  as an output code. While we compare with the gear-shifting algorithm, the modified bang-bang algorithm violently speeds up the lock-in time in 15µs (750 reference cycles).

Fig. 1.6 shows the architecture of the modified bang-bang algorithm. A cumulative multiplier which multiplies the proportional path is added before the loop filter. The integration path depends on the history record that works the same as the gear-shifting algorithm. While the PFD outputs three consecutive leadings, the proportional path increases as  $\beta$ ,  $2\beta$  and  $3\beta$ . Therefore, the ADPLL with the modified bang-bang algorithm can achieve fast lock-in.



Fig. 1.6: Architecture of Modified Bang-Bang Algorithm-Based ADPLL.

In [31], it discusses the coefficients in different integration paths  $(K_i)$  and proportional paths  $(K_p)$  and the step response of the ADPLL. As shown in Fig. 1.7, if  $K_p$  equals to 1, it can improve the lock-in time. A  $K_i$  equals to 500, it can accelerate the loop filter to stable the DCO. Obviously, [31] trades off between  $K_p$  and  $K_i$  to achieve fast lock-in time and low phase noise. As a result, the gear-shifting algorithm makes a lot of efforts on tuning the value between  $K_p$  and  $K_i$ . While the ADPLL is ported to different CMOS process, these values are needed to be adjusted.



Fig. 1.7: Step Response of the ADPLL under Different Loop Filter Parameters.

### **1.2.3 Frequency Counter Based Approach**

Using the time-to-digital converter (TDC) is another method to achieve fast lock. Recently, TDCs are widely used in ADPLLs design [17] [18] to search the frequency and quantify the phase error between the reference clock and the feedback clock. The TDC converts timing information into digital numbers. While using the TDC to convert the reference clock by the DCO clock, it acts like a counter that inputs a reference clock as data and the counter is triggered by the DCO clock. Then, the output is a ratio between the reference clock and the DCO clock.

In [17], a wide frequency multiplication range with seven-cycle lock-in time is proposed. It utilizes the TDC to acquire the target frequency. The features of [17] are that the ring delay line of the TDC is shared with the DCO delay line. In order to avoid the PVT variation, [17] uses the same delay cells to the TDC and the DCO in order to ensure that they have the same resolution. Fig. 1.8 shows the block diagram of the TDC. Moreover, it consists of an integer part and a fractional part to extend the quantization range of the TDC. In Fig. 1.8, the counter counts the integer part; latch and encoder count the fractional part.

However, the design challenge of [17] is at the TDC resolution which limits the maximum frequency of the input reference clock. In order to avoid the overflow problem in the TDC counter, the resolution of the ring delay line is not good. The worst TDC resolution in [17] is 170ps, thus the ADPLL input frequency can only accept the clock frequency lower than 350 kHz. If the input frequency is higher than 350 kHz, this method will have a large frequency error. Unfortunately, there are few applications work lower than 350 kHz.



Fig. 1.8: Architecture of TDC [17].

In [18], a 2-level flash TDC to achieve fast lock-in time within two reference cycles is proposed. It has a high resolution and low power consumption due to the 2-level flash TDC which also has a wide quantization range for the TDC as shown in Fig. 1.9. In order to enhance the TDC resolution and reduce the hardware complexity, the TDC only uses 12 D-type flip-flops.



Fig. 1.9: Architecture of 2-level flash TDC.

However, the 2-level flash TDC consists of MUX cells that the intrinsic delay of the MUX cell may worsen the resolution of the TDC. Fig. 1.10 shows the overall architecture of the ADPLL [18]. Designing a fine resolution TDC requires great efforts. For this reason, in this ADPLL, a pre-divider divides the reference clock into a lower frequency before quantizing by the TDC. Therefore, the effective TDC resolution can be improved. In addition the quantization result (TDC\_code) of the TDC will record in 6 bits. However the frequency multiplication factor becomes larger, it may have few bits which not been used, thus the TDC quantization error may increase with the frequency multiplication factor.



Fig. 1.10: Architecture of ADPLL [18].

#### **1.2.4 Frequency Estimation Algorithm**

The frequency estimation algorithm (FEA) can achieve faster lock-in time than the binary search algorithm (BSA). In addition, the frequency counter based approach is proposed in [4], [5], [10] and [13]. The frequency estimation algorithm takes the characteristics of the DCO and calculates the target frequency in a short time. In [4] and [10], they utilize a fine resolution and a high linearity DCO with the monotonic response to estimate the control code for the output frequency. In [5], it uses the Regula Falsi method, therefore it could deal with the DCO with nonlinear or nonmonotonic response. In [13], it proposes techniques that estimate and preset the control code for the ADPLL to reduce the settling time.

In [4], a fast-lock engine (FLE) that achieves two reference cycles lock-in time is proposed. The block diagram of the FLE is shown in Fig. 1.11(a). Fig. 1.11(b) shows the ordinary ADPLL circuit. At the beginning, the ADPLL runs at the minimum frequency and the maximum frequency with two inner DCOs, respectively. Subsequently, two frequency counters quantize the period ratio between the DCO and the reference clock at DCO minimum frequency and DCO maximum frequency into two parameters (i.e.  $R_{max}$  and  $R_{min}$ ), respectively. Consequently, the FLE uses two parameters to calculate the target DCO control code and sends it to the outer DCO. Then the ADPLL can work at the target frequency within two reference cycles.



Fig. 1.11: FEA-Based Frequency Synthesizer Architecture.

The frequency estimation algorithm requires a high linearity and a high DCO resolution to acquire a precise target frequency in two reference cycles. However, the differential non-linearity (DNL) of the proposed DCO [4] is larger than one LSB. Hence, the DCO [4] does not have a good linearity characteristic. Furthermore, the FEA-based ADPLL [4] uses two inner DCOs and one outer DCO that cost a large chip area. Besides, on-chip variation can cause these DCOs different that also increases the estimation error in the output frequency.

In [10], another FEA-based fast lock-in ADPLL is proposed by using only one DCO that can achieve fast lock-in within four reference clock cycles. The architecture of the cyclic TDC embedded DCO is shown in Fig. 1.12. Due to the frequency estimation algorithm, the DCO oscillates at the maximum frequency and the minimum frequency to calculate the period ratio in the first cycle and second cycle. Comparing with [4], [10] uses only a DCO and can avoid the on-chip variation problems in [4].



Fig. 1.12: Cyclic TDC embedded DCO.

Even though, the 63-stage D-type flip-flops (DFFs) could quantize the period ratio into a fixed point number to minimize the quantization effect of the TDC. Nevertheless, the cyclic TDC is only used for generating the period ratio at the minimum frequency of the DCO. As the DCO oscillates at the maximum frequency, the TDC can not quantize the period ratio with the fractional part. Consequently, the hardware utilization of the TDC [10] is not sufficient.

On the other hand, the DCO requires oscillating at minimum and maximum frequencies in order to estimate the control code for the target frequency. While the PVT variations are at the best case, the maximum frequency of the DCO may cause the DFFs setup time or hold time violations, for this reason, the operation of the DFFs become unpredictable. Therefore, the frequency finder [10] is not able to calculate the control code for the target frequency correctly in some worst cases.

In [5], a fast lock-in ADPLL by using the Regula Falsi method is proposed. Although the DCO is nonmonotonic or nonlinear, it claims that the ADPLL can lock the target frequency within seven reference cycles. In addition, the lock-in time of the Regula Falsi method is shorter than the binary search algorithm. As a general frequency estimation algorithm, the Regula Falsi Method also requires the DCO runs at maximum and the minimum frequency at the beginning. If the DCO is linear and monotonic, the first estimation result is the target frequency. Otherwise, they compare the first estimation result with the target N, if the estimation result is larger than the target N, the right bound is replaced by the result. Conversely if the estimation result is less than the target N, the left bound is replaced by the result and keep the right bound. Repeating this action until the result is equal to the target N.



Fig. 1.13: Example of the Regula Falsi Method.

For example, in Fig. 1.13,  $L_0$  is the first line which is used to estimate  $Code_0$ . However, as running a DCO with  $Code_0$ , the frequency ratio is larger than the target N. Subsequently, the right bound is replaced by the ratio upper bound (RUB) and keeps the left bound. Next, it utilizes  $L_1$  as a new line to estimate the result again. However the estimation result is less than the target N, it replaces the left bound by ratio lower bound (RLB) and keeps RUB as the right bound. Consequently using  $L_2$  for calculation, the result is equal to the target N. In the end, it outputs the control code to the DCO precisely.



Fig. 1.14: Worst case of the Regula Falsi Method.

The common DCO ratio between the reference clock and the DCO clock is illustrated in Fig. 1.14. While the curve of the DCO ratio operates in Fig. 1.14, it is hard to achieve fast lock-in time. In that case, the estimation result is less than the target N in several iterations, it always replaces the left bound and keeps the right bound. In this case, the Regula Falsi Method does not have a chance to adjust the right bound and converge the estimation line, therefore it requires many reference cycles to achieve lock-in in this example.



Fig. 1.15: Example of Locking Process in [13].

In [13], an equation that describes the relation between the target frequency and the steps in various modes during acquiring and tracking the frequency is proposed. As shown in Fig. 1.15, this figure shows an example. While tracking the frequency, the PVT calibration mode acquires the frequency toggles between 6 and 7 with  $\Delta f_p$ . Then, the PVT calibration mode locks the code at 6 and the residual frequency error is less than  $\Delta f_p$ . Using  $\Delta f_A$  as the medium frequency step, it acquires the frequency toggles between 4 and 5. Then the acquisition mode locks the code at 4, and then, the residual frequency error is less than  $\Delta f_A$ . In the tracking mode, the PLL uses the finest frequency step  $\Delta f_T$  to track the frequency in the same action as mention before. Therefore, the action of estimating the frequency can be described as Eq. 1.1.

$$f_{target} - f_{initial} = OTW_p \times \Delta f_p + OTW_A \times \Delta f_A + OTW_T \times \Delta f_T + \epsilon$$
(1.1)

$$OTW_{P} = \left( frequency \ Multiplication - \frac{f_{initial}}{f_{reference}} \right) \times \frac{f_{reference}}{\Delta f_{p}}$$
(1.2)

Fig. 1.16 shows the flowchart of the locking operation. As the ADPLL power on, it starts self-calibrating the process variations. In this stage, the ADPLL estimates the value of  $\Delta f_p$ ,  $\Delta f_A$  and  $\Delta f_T$  owing to the PVT variations which influence the value. Since the ADPLL obtains the value by the self-calibration, the PLL utilizes the value in estimating the control code (*OTW*) as shown in Eq. 1.2. In Eq. 1.2, firstly, the frequency multiplication subtracts the ratio of the initial frequency and the reference frequency and times the step ratio of step frequency and reference frequency that explains how many times of the step ratio requires to achieve the target frequency. Subsequently the ADPLL starts the normal operation to track the frequency. In the end, the ADPLL is turned off to reduce the power consumption.



Fig. 1.16: The Flowchart of ADPLL in [13].

Although this method can reduce the settling time by about 50%, the method requires the self-calibration in the beginning that is not efficient enough. On the other hand, the estimation equation requires a high DCO resolution to ensure the self-calibration is precisely enough. If the self-calibration is not accurate, it will generate a large frequency error during the estimation.

#### **1.2.5 Phase Calibration**

In order to achieve fast lock, tracking the frequency and phase concurrently is necessary. Due to the fact that the PFD is a sequential logic circuit which continuously outputs leads or lags of comparing the frequency and phase of the reference clock and feedback clock. Therefore, [1]-[4] present a phase calibration scheme to align the phase before entering the PFD in order to reduce the time of locking phase. For design a fast lock-in PLL, it is necessary to align the phase of the feedback clock at the beginning.

In [2], a single-shot phase synchronizer is proposed that synchronizes the reference clock and the feedback clock at the rising edges. The single-shot phase synchronizer combines with delay cells and latches. Each delay cell is arranged in pairs with a latch. Therefore, the feedback clock is fed to the delay cell that the delay cells are lined up in the delay line as shown in Fig. 1.17.



Fig. 1.17: Single-Shot Phase Synchronizer Schematic.

After the DCO is released from reset, the DCO starts working with the first rising edge of the reference clock. Then, the feedback clock is fed to the delay line which generates different phases. At the same time, the single-shot phase synchronizer delays a copy of the reference clock for synchronizing. The feedback clock is delayed by each delay cell and latched the value by the DCO clock. -22-

According to the latch value, the single-shot phase synchronizer can acquire the relative position of the feedback clock and the reference clock.

However, [2] uses the single-shot phase synchronizer at the beginning, the phase is synchronized in the first cycle of the acquisition state before fed into the PFD. In the second cycle, after the PFD detects leads or lags from the feedback clock and the reference clock, the frequency of the feedback clock is changed. As the frequency changes, the phase is not aligned. Besides, the single-shot phase synchronizer requires a multi-phase DCO. Additionally, the resolution of delay cell determines the phase error. Therefore, it is not suitable for high frequency operation.

In [3], a phase error compensation which can accumulate the phase error and adjust the frequency smoothly is proposed. This paper focuses on wireless communication applications which require frequency hopping. If a large initial phase error at the instant of frequency hopping, the PLL is unable to compensate for the large phase error immediately. Therefore, the long settle time is inevitable.



Fig. 1.18: Block Diagram of Phase Error Compensation.

The concept of the phase error compensation is dynamically modified the divider ratio as shown in Fig. 1.18. While the synthesizer jumps to another channel, the divider ratio changes form M to N. The error accumulator accumulates the phase error due to the frequency change. After the phase tracking mode, according to the output of the TDC, the divide ratio may decrease or increase that depends on M < N or M > -23-

N. If M < N, the divide ratio may decrease. In that case, the next edge of the divide clock arrives earlier to compensate for the large phase error as shown in Fig. 1.19. At the same time, the loop filter is adjusted to a wide bandwidth to speed up the locking process. After the locking process, the loop filter is adjusted to a narrow bandwidth to suppress the noise.

However, the FCW (Frequency Controlled word) which controls the divide ratio is inputted from outside the chip. Modifying the value from the outside of the chip is easy to design. For the reason that the ADPLL adjusts the value from outside the chip to reduce the PVT variations, it is more valuable to avoid PVT variations by on-chip circuits. However, adjusting the divide ratio to compensate the phase, the target frequency will drift away easily. Otherwise, it demands on a large divide ratio to decrease the target frequency drift. Besides, although the phase error compensation reduces the phase error continuously, the PLL still takes 25 reference cycles to lock-in due to the narrow bandwidth. **REF CLK FB CLK DCO Clock** Divider N - 3XN - 2XN - 1XN Ratio

Fig. 1.19: Compensating Timing Diagram.

In [4], they illustrate the phase-synchronized scheme between the reference clock and the DCO clock. In Fig. 1.20, the module "Phase Sync" which accumulates the phase error and outputs a sync signal. When the Phase Sync accumulates to a certain amount of error, the Phase Sync will trigger a sync signal to modify the control code. At the same time, a D flip-flop stops the DCO and waits for the next positive edge of the reference clock to restart the DCO. As shown in Fig. 1.22, the phase is aligned at the next positive edge of the reference clock.



Fig. 1.20: Architecture of the Phase Sync Scheme.

A lock detector (LD) is presented to set the accumulate window which determines when to start tracking the phase. The propagation delay decides the window of the LD that is consists of numbers of the delay buffer stages as shown in Fig. 1.21. M is the number of the buffer stages, and  $\epsilon$  as the gate delay of the buffer. The accumulate window can express as

 $W_{LD} = M \times \epsilon$ 

The application determines the total stages M. Therefore, the M is different in various applications which have different tolerance of the phase error.



Fig. 1.21: Schematic of Lock Detector.




In [10], this paper also uses an enable signal to turn on or off the DCO. As the enable signal sets to 1, the DCO starts working; as the enable signal sets to 0, the DCO stops working. It is more intuitive to design. Besides, restarting the DCO to initialize the phase error can reduce the costs of area and power consumption. In [4], [5], [9], [10], these papers design to restart the DCO to initialize the phase error. Consequently, the phase error is required to eliminate to achieve fast lock-in. While we compensate for the phase error, restarting DCO at the beginning is more efficient and more suitable.



Parameter	Application	Tracking Frequency	Phase Calibration	Gear Shifting	Lock-in Cycles
JSSC 2015 [1]	Global System for Mobile Communication	Binary Search	Phase Calibration State Machine	О	40 ( 100 ns )
TCAS-II 2012 [2]	Multiprocessor System-on-Chip	Binary Search	Single-Shot Phase Synchronization	Х	< 50 ( < 1 us )
A-SSCC 2012 [3]	Wireless Communication Industry	Binary Search	Phase Error Compensation	Х	25 ( 5 us )
TCAS-II 2007 [7]	Global System for Mobile Communication	Binary Search	Restart to Initial Phase	Ο	650 ( <50 us )
TCAS-II 2011 [8]	Wireless Transceivers	Binary Search	Modified Bang-Bang Algorithm	Х	750 ( 15 us )
ISCAS 2014 [5]	DDR Controllers USB2.0 USB3.0 SATA2 SATA3	Regula Falsi Method	Restart to Initial Phase	0	7
ICECS 2014 [6]	Wireless Communication Application	Temperature Compensation	Edge Detector	Х	45 ( 3 us )
TCAS-II 2010 [4]	Wireless Communication System	Frequency Estimation Algorithm	Restart to Initial Phase	Х	2
NEWCAS 2013 [9]	Wireless Communication Application	Temperature Compensation	Restart to Initial Phase	Х	120 ( 6 us )
TVLSI 2015 [10]	Biomedical Electronic Application	Frequency Estimation Algorithm	Restart to Initial Phase	Х	4

Table 1.2: Comparison Table of Fast Lock-in Methods

In Table 1.2, the table shows that applications apply to different methods which correspond to various lock-in cycles. Fast lock-in methods are widely employed in plenty of applications. According to this table, using the binary search algorithm to track the frequency and phase takes a long lock-in time than using the frequency estimation algorithm. However, although the frequency estimation algorithm can reach fast locking in few reference cycles, the accuracy and frequency error are an important issue required to concern. As a result, fast lock-in ADPLLs becomes a trend in recent years. Besides, how many percentages of the frequency error can be tolerated after frequency tracking is dependent on the applications.



### **1.3 Summary**

There are several ADPLL architectures we have discussed above. In different applications, they have advantages and disadvantages. Therefore, in this thesis, we proposed an FEA-based ADPLL for wearable device that demands on low power and low chip area. The proposed ADPLL is implemented in TSMC 40-nm CMOS process and achieves a fast lock-in time.

The proposed ADPLL improves the frequency estimation algorithm from [10] and [32]. We use the DCO medium frequency and the DCO maximum frequency to quantize the period ratio between the DCO clock frequency and the reference clock frequency. Therefore we can estimate the target DCO control code within 3.5 clock cycles. Then we compensate the estimated value in order to reduce the quantization error within 1 clock cycle. In addition, as the FEA scheme is finished, it outputs the target DCO control code to the DCO within 4.5 clock cycles.

Furthermore, we compare the DCO embedded-cyclic TDC proposed in [10]. Although the cyclic TDC can quantify the period ratio into a fixed point number, it occupies large area. We abandon the cyclic TDC and reduce the quantization error with an equation based on the DCO resolution. On the other hand, we follow the DCO regular placement approach proposed in [32], the regular placement approach improves the DNL of the DCO that makes the DCO more linear.

After the FEA scheme estimates the target DCO control code, the proposed ADPLL adjusts the DCO fine-tuning stage to maintain frequency and phase by the binary search algorithm. As a result, we proposed a fast lock-in ADPLL with low power, low chip area and high accuracy.

## **1.4 Thesis Organization**

In this thesis, the rest of the paper is organized as follow. Chapter 2 presents the proposed ADPLL architecture and the proposed frequency estimation algorithm. In addition we discuss fast lock-in frequency estimation issues. Chapter 3 describes the fast lock-in ADPLL circuit implementation that includes the monotonic digital controlled oscillator, the digital loop filter, the phase and frequency detector and output frequency divider. The specifications and the simulation results of the proposed fast lock-in ADPLL are presented in Chapter 4. Finally, in Chapter 5, we make a conclusion of this thesis and discuss some issues which should be improved in near further.



# **Chapter 2**

# Fast Lock-in All Digital Phase Locked Loop

#### 2.1 The Proposed Fast Lock-in ADPLL



Fig. 2.1: The Block Diagram of the Proposed ADPLL.

A fast lock-in ADPLL approach is proposed in this section and it is implemented in TSMC 40-nm CMOS process. The fast lock-in ADPLL is composed of a phase frequency detector (PFD), an ADPLL controller with a digital loop filter, a monotonic DCO, a frequency divider, a frequency finder, a cyclic counter and an output divider.

Fig. 2.1 shows the block diagram of the proposed ADPLL. In the beginning, the PFD and frequency divider are stopped waiting for the frequency finder to estimate the target DCO control code (init\_code). Subsequently, the ADPLL controller acquires the DCO control code and sends to the DCO. We apply a similar FEA-based [10] [4]

fast lock-in method in the ADPLL controller. However, [4] requires a fine resolution and a high linear characteristic of the DCO. Otherwise the frequency estimation error becomes large. Therefore, after estimating target frequency, [4] requires extra several cycles to track the target frequency with a large frequency estimation error. Besides, using a frequency counter without any calibration methods cause the large quantization error. Furthermore, three DCOs occupy huge chip area and cause the on chip variations. [10] exploits an embedded cyclic-TDC in order to minimize the quantization error. However, it also costs a lot of area due to the cyclic-TDC.

Therefore, we proposed a calibration algorithm to reduce the quantization error in [10] without a TDC. The calibration algorithm is based on a DCO resolution. We utilize the monotonic characteristic of the DCO to find out the relation between the DCO control code and the ratio between the DCO clock and the reference clock. Finally, the frequency finder estimates a calibration value and calculates the DCO control code within 4.5 cycles.

Subsequently, the PFD and the frequency divider are enabled. The PFD continuously detects the phase and the frequency relation between the feedback clock and the reference clock. At the same time, the PFD updates the DCO control code in order to avoid the phase error or frequency drift. Then, the ADPLL controller receives the DCO control code and communicates to the digital loop filter. The digital loop filter generates the baseline DCO control code in order to reduce the reference jitter and stabilize the DCO output clock.

#### 2.2 The Proposed Frequency Estimation

#### CLK STATE Reset N R\_mid R max Calibration Calculation Maintenance RESET 1023 2047 Initial code DCO Code 0 Enable\_DCO DCO Clock Lock Feed Back Clock (R max-R mid) Dividend 0 2^11 2×18 W\_T - W\_min ×1023×2^18 R max×R Divisor R\_mid R\_may L\_mid -0 W\_min 20111-207 W\_min Quotient W\_T W\_mid L\_mid Initial code

## Algorithm

Fig. 2.2: Timing Diagram of the Proposed ADPLL.

The timing diagram of the frequency estimation algorithm with the proposed calibration method is shown in Fig. 2.2. After reset, the frequency finder computes the reciprocal of the multiplication factor (N) within a half cycle. When the DCO control code is set to the medium value of the DCO control code (DCO Code = 1023), the DCO operates at the median frequency with the median period, denoted as  $P_{mid}$ . Additionally, when the DCO control code is set to the maximum value of the DCO operates at the median frequency with the maximum value of the DCO control code (DCO Code = 2047), the DCO operates at the maximum frequency with the minimum period, denoted as  $P_{min}$ .

Subsequently, we utilize the median period  $(P_{mid})$  and the minimum period

 $(P_{min})$  to calculate the  $R_{mid}$  and the  $R_{max}$  by using the cyclic counter. The definition of the  $R_{mid}$  and the  $R_{max}$  is the ratio between the reference clock period  $(P_{ref})$  and the DCO clock period at the median frequency and the minimum frequency respectively. The mathematical formula to describe  $R_{mid}$  and  $R_{max}$  is expressed in Eqs. 2.1 and 2.2. The  $R_{mid}$  is the reference clock period divided by the medium clock period and the  $R_{max}$  is the reference clock period divided by the minimum clock period.

$$R_{mid} = \frac{P_{ref}}{P_{mid}} \tag{2.1}$$

$$R_{max} = \frac{P_{ref}}{P_{min}} \tag{2.2}$$

The reciprocal of the *R* value is defined as *W* value. The definitions of  $W_{mid}$  and  $W_{min}$  are expressed in Eqs. 2.3 and 2.4.

$$W_{mid} = \frac{2^{11}}{R_{mid}}$$
 (2.3)

$$W_{min} = \frac{2^{-1}}{R_{max}}$$
(2.4)

After *R* values and *W* values are defined, their relation is shown in Fig. 2.3. This figure shows the *R* value and *W* value corresponding to the DCO control code (DCO\_code). However, in this figure, the *R* value is assumed to be estimated by the cyclic TDC proposed in [10]. Thus *R* value is a fixed-point number. Obviously, the function of *R* value with DCO code is a hyperbola; the function of the *W* value with DCO code is a straight line. In [4], it exploits the *R* code function to estimate the DCO control code as a line that is not accurate enough.



Fig. 2.3: The relationship of *R* value and *W* value.

However, [10] defines and utilizes the *W* code function to estimate the DCO control code precisely with a fixed-point *R* value. As the *W* code function is approximate to a straight line, we can use the linear equation to calculate the target DCO control code. Therefore, the equation of the *W* (code) can be expressed as Eq. 2.5. The interval of  $W_{min}$  and  $W_{mid}$  times the target code and plus the  $W_{min}$  is the target code.

$$W(\text{code}) = W_{min} + \frac{(W_{mid} - W_{min}) \times 2}{2^{11} - 1} \times code$$
 (2.5)

However, the *W* code function in Fig. 2.3 is quantified by the cyclic TDC [10]. When we remove the TDC, since *R* value becomes an integer value, the straight *W* line becomes serrated. If we estimate the DCO control code with a serrated line, the quantize error will significantly affect the accuracy of the estimation result. Fig. 2.4 -35shows the relation between the W code function and the DCO control code in three process corners according to the simulation result with integer R values. First of all, the W line becomes trapezoid, so that is not able to use the linear equation any more. Besides, the quantization error is large especially when the target DCO control code is small and at the SS corner.



Fig. 2.4: The Relationship of the DCO Control Code and the W Value.



Fig. 2.5: The Quantization Error of the W Value without TDC.

According to the simulation in Fig. 2.4, we use the minimum value and maximum value of the W value to create a straight line, and then the quantization error is shown in Fig. 2.5. Therefore, the quantization error is small at the FF corner or with the larger DCO control code as shown in Fig. 2.5. In other words, while the DCO operates at the higher frequency, the quantization error to compute the integer R value is gradually decreased. As a result, we decide to exploit the medium and maximum frequency of the DCO as both ends of the line, so that can minimize the quantization error.

However only utilize the medium and maximum frequency of the DCO is not accurate enough, we provide a calibration method to reduce the quantization error of the *W* line. We define three parameters as follow.

- $T_0$  : The minimum clock period of the DCO.
- $\Delta$  : Fine-tuning resolution.

#### T : The period of the reference clock.

First, we explain the *R* value in another way. As we mention before, the *R* value is the period ratio between the DCO clock and the reference clock. The  $R_{max}$  is the number of how many minimum DCO clock periods in a reference clock period. We can describe  $R_{max}$  in the mathematical formula as Eq. 2.6. In this thesis, we only quantize one half cycle of the DCO minimum clock period and denoted as  $R_{max}$ . Then  $R_{mid}$  can be described as Eq. 2.7, and  $R_{mid}$  is the period ratio when the DCO control code is set to 1023.

$$R_{max} = \frac{\frac{T}{2}}{T_0} \tag{2.6}$$

$$R_{mid} = \frac{\frac{T}{2}}{T_0 + 1023\Delta}$$
(2.7)

According to Eq. 2.6 and Eq. 2.7, we express the  $\Delta$  and  $T_0$  in terms of  $R_{mid}$ and  $R_{max}$ . First, Eq. 2.6 is derives Eq. 2.8. Then  $T_0$  is expressed in terms of  $R_{max}$ and *T*. According to Eq. 2.7, we substitute Eq. 2.8 into Eq. 2.7 and derive Eq. 2.9. Subsequently, from Eqs. 2.9 to 2.13, the fine-tuning resolution ( $\Delta$ ) can be derived in terms of *T*,  $R_{mid}$  and  $R_{max}$ .

$$T_0 = \frac{\frac{T}{2}}{R_{max}}$$
(2.8)

$$R_{mid} = \frac{\frac{T}{2}}{\frac{T/2}{R_{max}} + 1023\Delta}$$
(2.9)

$$\frac{\frac{T}{2}}{R_{max}} + 1023\Delta = \frac{\frac{T}{2}}{R_{mid}}$$
(2.10)

$$1023\Delta = \frac{\frac{T}{2}}{R_{mid}} - \frac{\frac{T}{2}}{R_{max}}$$
(2.11)

$$1023\Delta = \frac{\frac{T}{2} \times (R_{max} - R_{mid})}{R_{mid} \times R_{max}}$$
(2.12)

$$\Delta = \frac{\frac{1}{2} \times (R_{max} - R_{mid})}{1023 \times R_{max} \times R_{mid}}$$
(2.13)

The general formula of the period ratio *R* (DCO\_code) can be expressed in Eq. 2.14.  $T_0$  in Eq. 2.14 can be substituted by Eq. 2.8, and  $\Delta$  can be substituted by Eq. 2.13, and then Eq. 2.15 can be derived. Subsequently, Eq. 2.15 and 2.16 are derived.

$$R(DCO\_code) = \frac{\frac{T}{2}}{T_0 + DCO\_code \times \Delta}$$
(2.14)

$$R(DCO\_code) = \frac{\frac{T}{2}}{\frac{T}{R_{max}} + DCO\_code \times \frac{\frac{T}{2} \times (R_{max} - R_{mid})}{1023 \times R_{max} \times R_{mid}}}$$
(2.15)  
$$R(DCO\_code) = \frac{1023 \times R_{max} \times R_{mid}}{1023 \times R_{mid} + DCO\_code \times (R_{max} - R_{mid})}$$
(2.16)

Since  $W(DCO\_CODE)$  is the reciprocal of  $R(DCO\_code)$ , and Eq. 2.17 can be easily derived. Eq. 2.17 shows the compensated W lines equation. Fig. 2.6 shows the DCO control code is set to 0 to 1200 because of a large quantization error in this portion. Obviously, the trapezoid line (Simulation W) is now close to the ideal W line (Conpensation W). As a result, we obtain a relation between W value and the DCO control code precisely by the calibration method. We can estimate the desire DCO control code with the linear equation expressed in Eq. 2.17.

$$W_{DCO\_code} = \frac{1023 \times R_{mid} + DCO\_code \times (R_{max} - R_{mid})}{1023 \times R_{max} \times R_{mid}} \times 2^{11}$$
(2.17)



Fig. 2.6: The Relationship Between the Trapezoid Simulation W and the

Compensate *W* line.  

$$L_{mid} = \frac{1023 \times R_{mid} + 1023 \times (R_{max} - R_{mid})}{1023 \times R_{max} \times R_{mid}} \times 2^{11} \qquad (2.18)$$

$$L_{mid} = W_{min} + \frac{R_{max} - R_{mid}}{R_{max} \times R_{mid}} \times 2^{11}$$
(2.19)

Consequently, we set DCO\_code to 1023 into Eq. 2.17 and calculate the calibration value that is defined as  $L_{mid}$  and expressed in Eq. 2.18. After simplifying Eq. 2.18, we obtain Eq. 2.19 which is easy to be implemented by hardware. From  $W_{min}$  and  $L_{mid}$  of the compensation W line, the equation of the line can be expressed in Eq. 2.20. The frequency multiplication factor of the ADPLL is the ratio between the reference clock period and the target DCO clock period. Hence the target period ratio ( $R_T$ ) is equal to the frequency multiplication factor (N); and thus  $W_T$  is

equal to 1/N. Therefore, we can estimate the target DCO control code (*init\_code*) by Eq. 2.20.

$$init\_code = 2^{10} \times \frac{W_T - W_{min}}{L_{mid} - W_{min}}$$
(2.20)





Fig. 2.7: The W Value Before Calibration and After Calibration.

We proposed a calibration method to eliminate the cyclic TDC in [10] and calibrate the  $W_{mid}$  to the  $L_{mid}$  as shown in Fig. 2.7. The  $L_{mid}$  is lower than the  $W_{mid}$  due to the integer *R* value. The reciprocal of the fixed-point *R* value is less than the reciprocal of the *R* integer. The proposed calibration method compensates the quantization error of *W* line. Furthermore, by adjusting the  $W_{mid}$  to the  $L_{mid}$ , we improve the accuracy of the FEA. Therefore, we can achieve a fast lock-in ADPLL precisely with the frequency estimation algorithm and the calibration method.

As shown in Fig. 2.2, in the first cycle, after reset, we compute the reciprocal of the frequency multiplication factor (N) into the  $W_T$ . Subsequently, the  $R_{mid}$  is

calculated by the cyclic counter; the  $W_{mid}$  is calculated by the frequency counter in the same cycle (R\_mid state). Consequently, the  $R_{max}$  and the  $W_{min}$  are calculated (R\_max state). After we obtain the  $R_{max}$  and the  $W_{min}$ , we start to compensate the quantization error and generate a calibration value  $L_{mid}$  in the third cycle (Calibration state). Then, the ADPLL controller can calculate the target DCO control code by Eq. 2.20 (Calculation state). Finally, the ADPLL controller can output the target DCO control code after 4.5 cycles.



#### 2.3 Summary

In Fig. 2.8, the frequency track of the ADPLL is shown, and the target frequency is 260MHz. In the first 4.5 cycles, the proposed ADPLL estimates the frequency closed to the target frequency. Subsequently, the binary search algorithm and the loop filter are applied to fine-tune the output frequency and keep maintaining the frequency and phase of the output clock. Therefore, after 4.5 cycles, the lock signal is pulled up, and the proposed ADPLL can provide the stable frequency output during fine-tuning.



Fig. 2.8: The Frequency Analysis at 260MHz.

As compares to [4] and [10], the proposed the calibration method based frequency estimation algorithm has a better hardware utilization and a precise prediction of the target frequency. Comparing with [4], although it can achieve fast lock within two cycles, the quantization leads to a large estimation error after two cycles. Besides three DCOs also cause the on-chip variation, it brings out each -43-

independent variable into the frequency estimation algorithm which requires relevant values.



Fig. 2.9: The frequency error Analysis with 150MHz.

We compare the frequency error between [4] and the proposed ADPLL as shown in Fig. 2.9. We set the multiplication factor in 30 and the target frequency is 150MHz. Obviously, after two cycles, [4] still remains a large frequency error which is almost 40%. Due to the large frequency error, [4] needs to track the target frequency with the binary search algorithm. Thus, actually it takes more than 50 reference cycles to achieve lock. However the proposed ADPLL requires 4.5 cycles to estimate the target frequency, the frequency error keeps under 1% after the 5<sup>th</sup> reference clock cycle.



Fig. 2.10: The initial frequency error between the proposed ADPLL and [4].

In Fig. 2.10, after estimating the target frequency, we compare the frequency error between [4] and the proposed ADPLL at the fifth reference clock with different N value. The frequency error of [4] is very large after the frequency estimation. However, while the multiplication ratio increases, the frequency error can be decreased.

In [10], a cyclic TDC is applied to minimize the quantization error, it improves the accuracy of frequency estimation indeed. It utilizes a DCO to avoid on-chip variations in [4]. However, the cyclic TDC [10] occupies large chip area and the efficiency of hardware utilization is not satisfied. In Fig. 2.11, this figure shows the frequency error in different multiple factors after the frequency estimation. We compare the proposed ADPLL with [10] with a 5MHz reference clock. Although [10] solves the issue in [4], the proposed ADPLL further increases the utilization of the hardware and improves the initial frequency error under 1%.



Fig. 2.11: The initial frequency error between proposed and [10].

# **Chapter 3**

# **Circuit Design and Implementation** of **ADPLL**

In this chapter, we describe the circuit design in the proposed fast lock-in ADPLL in 40-nm CMOS process that contains a monotonic DCO, a digital loop filter, a phase and frequency detector and a frequency detector.

# **3.1 Monotonic Digital Controlled Oscillator**



Fig. 3.1: The Proposed DCO.

In Fig. 3.1, the architecture of the monotonic DCO is shown. The proposed DCO is composed of 63 coarse-tuning stages [10] and 31 fine-tune stages [12].

#### **3.1.1 Coarse-Tuning Stage**

The coarse-tuning stages are applied in NAND-based architecture [10] as shown in Fig. 3.2. Four NAND gates constitute a coarse-tuning stage. The 1<sup>st</sup> NAND gate is operated like a switch that controls this coarse-tuning stage to be on or off. The 2<sup>nd</sup> and the 3<sup>rd</sup> NAND gate provide the delay time, thus, the coarse-tuning resolution is dependent on the 2<sup>nd</sup> and the 3<sup>rd</sup> NAND gates. The 4<sup>th</sup> NAND gate is used to balance the rise time and the full time due to that each input node has equal capacitance loading. While the 4<sup>th</sup> NAND gate balances the coarse-tuning rise time and full time, the duty cycle will not be distorted by the unbalanced rise time and full time, as shown in table 3.1.



Fig. 3.2: The Proposed Coarse-Tuning Stage.

Table 3.1: The DCO Duty Cycle in 40-nm CMOS Process.

Parameter	129MHz	1.47GHz	
Duty Cycle	51.11%	47.27%	

The coarse-tuning stage is controlled by the coarse control code (coarse[n]). We assume that the coarse control code is 63'hffff\_ffff\_ffff (coarse [0] ~ coarse [1] = 0, coarse [2] ~ coarse [62] = 1) as shown in Fig. 3.3, the delay path pass through the group of coarse [2]. Therefore, as the delay cells are unused, they can be gated by the coarse control code that can reduce the dynamic power consumption of the DCO.



Fig. 3.3: The Coarse-Tuning Stage Delay Path.

The coarse-tuning stage structure has high linearity between the coarse control code and the output period due to the regular placement approach [32]. In Fig.3.1, the minimum delay path is the shortest delay path of the coarse-tuning stage; the maximum delay path is the longest delay path of the coarse-tuning stage. As a result, the proposed coarse-tuning stages can provide a wide frequency range in various coarse control codes.



Fig. 3.4: The Fine-Tuning Stage of the Proposed DCO.

The fine-tuning stage architecture of the DCO is shown in Fig. 3.4. The fine-tuning stage is composed of two parallel connected tri-state buffer arrays [12]. The two parallel connected tri-state buffer arrays operate as an interpolator circuit which is controlled by the fine control code. We use 31 tri-state buffers to interpolate the signal CA\_OUT and the signal CB\_OUT. The different between the CA\_OUT and the CB\_OUT is a coarse-tuning stage. Utilizing the fine control code (Fine[n]), the total controllable range is always equal to a coarse-tuning stage.

The traditional fine-tuning stage of the DCO requires overlapping the coarse-tuning stage. As the PVT variation affects the DCO, the traditional fine-tuning stage without overlap may lose some frequencies. Besides, while switching the coarse control code, the cycle-to-cycle jitter of the DCO becomes worse. Therefore, we utilize the two parallel connected tri-state buffer arrays as the fine-tuning stage not only improves the resolution of the DCO, but also ensure the total fine-tuning range is a coarse-tuning stage.

The principle of the two parallel connected tri-state buffer arrays is utilized the driving strength of the tri-state buffer arrays to generate various delay time. While the more left-hand side tri-state buffers are turned on, the output clock (OUT\_CLK) is closer to the CA\_OUT. Conversely, while the more right-hand side tri-state buffers are turned on, the output clock is closer to the CA\_OUT. We suppose that the fine control code is 5'd29, the fine control code should encode as 31'h7fff\_ffff (Fine [0] ~ Fine [28] = 1, Fine [29] ~ Fine [30] = 0). The delay time between the CA\_OUT and the CB\_OUT can be considered as divided into 31 portions as shown in Fig.3.5. Therefore, the output clock is more close to the signal CA\_OUT.



Fig. 3.5: The Timing Diagram of the Fine-Tuning Interpolation Signal Illustration.

Besides, the DCO control code has 11 bits. A DCO Encoder encodes the 11 bits DCO control code into the coarse-tuning and fine-tuning control thermometer codes. The dco\_code [10:5] and the dco\_code [4:0] encodes into coarse [62:0] and fine [31:0], respectively.

Furthermore, the proposed DCO can operate in a wide range during low voltage. The frequency range of various operating voltage in 40-nm is shown in table 3.2. The normal operating voltage in 40-nm is 0.9V. As we demand for low operating voltage to decrease power consumption, the proposed DCO can still operate in wide frequency range. However, the results are the pre-layout simulation. As the process is scaling down to the deep submicron CMOS process, the interconnection delay has great impact on the total delay. Therefore, in pre-layout simulation, the DCO frequency range is not accurate enough. After automatic placement and routing (APR) is done, delay cells are connected by wires. Subsequently, the wire delay is considered in post-layout simulation, we should depend on the post-layout simulation to analyze -51-

the DCO frequency range.

For example, in the pre-layout simulation at 0.9V supply voltage, the DCO maximum frequency is adjusted at 5.9GHz, after APR, the DCO maximum frequency in post-layout simulation is only 2GHz. In the pre-layout simulation at 0.5V supply voltage, the DCO maximum frequency is adjusted at 857MHz, after APR, the DCO maximum frequency is 264MHz.

As a result, the proposed DCO with the fine-tuning stage and the coarse-tuning stage can achieve wide frequency range and monotonic response in the output clock versus the DCO control code. In addition the proposed DCO minimizes the jitter during the coarse control codes switching.

Table 3.2: The DCO Frequency Range in Different Operating Voltage in

Pre-Layout Simulation and Post-Layout Simulation

Operating Voltage (V)		0.5	0.6	0.7	0.8	0.9
Frequency	Pre-Layout Simulation	65 ~ 857	142 ~ 1869	<mark>238 ~ 3</mark> 154	341 ~ 4566	441 ~5896
(MHz)	Post-Layout Simulation	33 ~ 264	76 ~ 606	134 ~ 1123	200 ~ 1519	256 ~2024

#### **3.1.3 The Proposed Regular Placement Method**

As the process technology is scaling down to the deep submicron CMOS process, the interconnection delay has great impact on the total delay connection. Therefore, the relative locations between delay cells during the automatic placement and routing (APR) are controlled by the regular placement approach [32].

The wire lengths between the delay cells of the DCO are determined by the APR tools. Once the area constraints and the cell placement results are changed, the routing results will be changed accordingly. Hence, the DCO regular placement approach is presented to avoid the large wire length variations in different DCO placement cases.



Fig. 3.6: The Regular Placement of the DCO

Fig. 3.6 shows the layout of the DCO including the coarse-tuning stages and the fine-tuning stages. When the coarse-tuning stages are placed closer, the wire length between the pins of the delay cells becomes shorter. Besides, the wire length between two neighboring coarse-tuning stages can be controlled almost the same which also improves the differential nonlinearity (DNL) of the coarse-tuning stage.

Fig. 3.7 shows the DNL comparison results between the regular placement and random placement by the APR tools in  $150 \times 80 \,\mu m^2$ . In addition, the serrated edge of the DNL results is due to well taps and stripes. The maximum DNL of the proposed DCO regular placement is lower than 0.3 LSB and higher than -0.2 LSB. Therefore, the proposed DCO has a monotonic response.



Fig. 3.7: DNL Comparison of the DCO in  $150 \times 80 \ \mu m^2$ .

#### **3.2 Phase and Frequency Detector**

We adopt the architecture of the cell-based bang-bang phase and frequency detector (PFD) which is proposed in [11]. The PFD outputs the UP signals or the DN signals between the reference clock (REF\_CLK) and the feedback clock (FB\_CLK). In Fig. 3.8, the proposed PFD consists of buffers, inverters, NAND gates and DFFs which depends the dead zone of the PFD. The dead zone is the smallest detectable phase error of the PFD. As we compare with the phase detector, the phase detector can only detect the phase error. According to the continuous UP signals or DN signals, the PFD outputs to the ADPLL controller to adjust the DCO output frequency.



Fig. 3.8: The Proposed phase and frequency detector.

However, the digital pulse amplifier [11] is the indispensable part in promoting the performance of the PFD. If the phase error between the reference clock and the feedback clock is very small, the narrow pulse width is not able to trigger the DFF reset pin (RST). Therefore, the digital pulse amplifier extends the phase error between the reference clock and the feedback clock so that the pulse width is wide enough to reset the DFF. The architecture of the digital phase amplifier is shown in Fig. 3.9. It utilizes the cascade two-input AND gates architecture to increase the narrow pulse width for RST pin.



Fig. 3.9: The Digital Pulse Amplifier Architecture.

As a result, the proposed PFD is able to output the UP signals and the DN signals continuously. It can not only detect the phase error, but also the frequency error. Besides, in 40-nm, the dead zone of the PFD is 17ps so that it can detect the slight phase error which the reference clock is very close to feedback clock.

### **3.3 Test Chip Implementation**

The proposed frequency divider is designed for chip measurement at high frequency operation. Due to the clock rate on I/O pads, signals operate at high frequency are unable to transmit through I/O pads in TSMC 40nm cell-library.



Fig. 3.10: Frequency Divider Architecture.

In Fig. 3.10, the frequency divider is adopted the cascaded divide-by-2 frequency divider architecture. The proposed frequency divider is consisted of multiplexers and -55 -

four DFFs. The multiplexers are used to select the signals in various division ratios. The DFFs are asynchronous binary counter clocked by the input signal (DCO\_CLK). The frequency of the DCO\_CLK\_DIV2 signal is half of the DCO\_CLK frequency and so on the DCO\_CLK\_DIV4 signal is a quarter of the DCO\_CLK frequency. Each stage divides signals by 2. Therefore, the proposed frequency divider can divide the DCO\_CLK signal to the OUT\_DIV\_CLK signal by  $2^m$ , where *m* is the stage number.

The feature of the cascaded divide-by-2 frequency divider is that it can deal with a very fast signal input. However, the cascaded divide-by-2 frequency divider can only be used for power-of-2 integer division.



Fig. 3.11: The Phase Error between REF\_CLK and OUT\_DIV\_CLK Illustration. In the standard cell library, due to the worse transition time and rise delay of the DFFs, the frequency divider produces a clock skew between the REF\_CLK and the OUT\_DIV\_CLK. Fig. 3.11 shows the phase error between the REF\_CLK and the OUT\_DIV\_CLK.



Fig. 3.12: ADPLL Frequency Tracking Procedure.

The ADPLL continues tracking the frequency and the phase of the reference clock by the DCO control code. The digital loop filter [19] [43] is required to stabilize the DCO control code and maintain the output frequency. Fig. 3.12 describes the tracking process of the ADPLL. In Region I, the ADPLL estimates the target frequency. After entering Region II, the output frequency of the DCO is close to the target frequency. However, it still has small frequency error and phase error. When the ADPLL suffers from the reference clock jitter or supply noise, the output frequency of the DCO becomes unstable in Region II. Therefore, the digital loop filter can overcome the reference clock jitter or supply noise and stabilize the loop.

The digital loop filter structure [43] is shown in Fig. 3.13. The digital loop filter obtains the DCO control code from the ADPLL controller output. After the target DCO control code sends to the DCO, the digital loop filter stores the DCO control

code in each reference cycle. In addition, the digital loop filter stores eight DCO control codes to generate a baseline DCO control code. If eight DCO control codes are already stored in the digital loop filter, an ff\_init\_ok signal is triggered to generate the baseline DCO control code. Subsequently, every two new DCO control codes are sent to the digital loop filter, the digital loop filter sorts the DCO control codes. Consequently, the digital loop filter removes both the minimum and the maximum stored DCO control codes, and the digital loop filter generates the baseline DCO control codes, and the digital loop filter generates the baseline DCO control code by averaging the rest of the DCO control codes ( $C_0, C_1, ..., C_7$ ). Therefore, the baseline DCO control code is updated by the digital loop filter. As a result, the proposed digital loop filter updates the baseline DCO control code in a short time and stabilizes the output frequency of the DCO.



Fig. 3.13: The Digital Loop Filter Structure [43].

# **Chapter 4**

# **Full Chip Experimental Results**

# 4.1 Specifications



(a)



(b)



(c)

Fig. 4.1: (a) Layout of the Test Chip without the Dummy cell. (b) Layout of the Test Chip with the Dummy cell. (c) Layout of the Test Chip with the Bonding Pad

Block Number	Module Name
(1)	Phase and Frequency Detector (PFD)
(2)	ADPLL Controller

Table 4.1: Block Module Name.
(3)	Frequency Finder		
(4)	Cyclic Counter		
(5)	Digital Loop Filter (DLF)		
(6)	Digital Controlled Oscillator (DCO)		
(7)	Output Divider		
(8)	Frequency Divider		

The proposed fast lock-in ADPLL is implemented in TSMC 40-nm UTM CMOS process. The complete chip layout is shown in Fig. 4.1(a). In addition, the chip layout with the dummy cells is shown in Fig. 4.1(b). Fig. 4.1(c) shows the chip layout with the bonding pads. The active area is  $120 \times 120 \ \mu m^2$  and the chip area including I/O pads is  $620 \times 620 \ \mu m^2$ . In Table 4.1, the block module names are listed. The chip consists of the ADPLL and the test chip circuit. The gate count on the chip is about 6,965. The simulated power consumption is 0.511mW at the test mode = 1 and the test n = 5 with 0.9V supply voltage.



Fig. 4.2: Chip Floorplan and I/O Plan.

The chip I/O planning and the floorplanning of the proposed ADPLL are described in Fig. 4.2. The proposed ADPLL test chip is designed with 13 input pins, 6 output pins, and 13 power pins. The detail I/O pads information are shown in Table 4.2.

Input	Bits	Function			
REF_CLK	1	Reference input clock			
RESET	1	Initial the chip at 0			

Table 4.2: I/O PAD Description.

			Value	Function	
I_change_function	1		1'b0	Original Function	
		1'b1		Improving Function	
		Set the multiplication factor of ADPLL			
			Value	Factor code	
			4'd0	2	
			4'd1	4	
			4'd2	8	
			4'd3	16	
			4'd4	32	
			4'd5	64	
Test_N	4	4'd6		128	
		4'd7 4'd8		256	
				7	
		/	4'd9	13	
			4'd10	19	
		4'd11		23	
		4'd12		47	
		4'd13		73	
		4'd14		131	
			4'd15	257	
		Divide frequency of the output clock			
	2	Value Function		Function	
М		2'd0 Divide factor = 2 (test chip)			
		2'd1	Divide f	actor = 4 (test chip)	

		2'd2	Divide factor = $8$ (test chip)			
		2'd3	Divide factor = 16 (test chip)			
			Set the test mode of the chip			
		Value	Function			
		3'd0		Fixed DCO at minimum		
				frequency		
		3'd1	Block	Tracking frequency		
Test_Mode	3	3'd2	3'd2 DCO_CLK Fixed DCO at first ca			
				code		
		3'd3	Fixed DCO at maximum			
			frequency			
		3'd4		Fixed DCO at minimum		
				frequency		
		3'd5	Block	Tracking frequency		
		3'd6	DIV_CLK	Fixed DCO at first calculation		
				code		
		3'd7		Fixed DCO at maximum		
				frequency		

In Table 4.2, we design a 3-bit Test\_Mode. Before measuring the chip performance, we require to figure out whether the chip is in FF corner, SS corner or TT corner. Therefore, we have four modes testing the minimum frequency and the maximum frequency of the chip. Besides, if two I/O pads output signals simultaneously, two signals may interfere with each other. Therefore, we block a clock signal during measuring the other clock signal.

# **4.2 Simulation Results**

### 4.2.1 Test Mode Simulation

The post-layout simulation result of the proposed ADPLL in various test modes is shown in Fig. 4.3. The dco\_clk or the div\_clk are blocked in different test modes. In addition, the div\_clk is operated at test modes 1 to 3; the dco\_clk is operated at test modes 4 to 7. The detail functions of each mode are shown in table 4.2. Therefore, as we measure the clock signals, the clock signals may not be interfered by each other.



Fig. 4.3: System Simulation of the proposed ADPLL with various test modes.

In Fig. 4.4(a), Fig. 4.4(b) and Fig. 4.4(c), we simulate the proposed ADPLL in TT corner, FF corner and SS corner, respectively. We set the test mode at 1 so that the dco\_clk is disable output. The proposed fast lock-in ADPLL can lock correctly in different corner simulation.



#### (a)



#### (b)



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Fig. 4.4: System Simulation of the proposed ADPLL with PVT Variation.

(a) Post-Sim at 0.9V, Ref\_clk = 5MHz, TT corner, Temperature  $25^{\circ}C$ 

(b) Post-Sim at 0.99V, Ref\_clk = 5MHz, FF corner, Temperature  $-40^{\circ}$ C

(c) Post-Sim at 0.81V, Ref\_clk = 5MHz, SS corner, Temperature 125°C

### 4.2.2 Chip Summary

Process	40-nm CMOS		
Core Area	$0.0144 \ mm^2$		
Chip Area	0.3844 mm <sup>2</sup>		
Lock-in Time	4.5 cycles		
Supply Voltage	0.9V		
Time Resolution	3.43ps		
Operating Range	129.8MHz~1.47GHz		
	0.3749mW @ 129.8 MHz		
Power Consumption	0.981mW @ 1.47GHz		

Table 4.3: Chip Summary.

The chip summary is shown in Table 4.3. The core area and the chip area is 0.0144*mm*<sup>2</sup> and 0.3844*mm*<sup>2</sup>, respectively. The operating frequency range of the proposed ADPLL is about 130MHz to 1.47GHz. In addition, the power consumption of the proposed ADPLL at 129.8MHz is 0.3749mW with 0.9V supply voltage. Besides, the DCO dominates the power consumption of the ADPLL. The power consumption of the DCO is 0.2674mW and 0.8918mW at 129.8MHz and 1.47GHz as shown in Table 4.4. In addition, the power consumption simulation results of the

ADPLL with PVT variations are shown in Table 4.5. The power consumption at 320MHz is 0.511mW, 1.1mW and 0.343mW in typical case, best case and worse case, respectively.

Parameter	DCO @129.8MHz	DCO @ 1.47GHz		
Power	0.2674mW	0.8918mW		
Consumption	0.2074IIIW	0.8918IIIW		

Table 4.4: The DCO Simulation with Different Frequencies.

Table 4.5: Simulation with PVT Variations.

Parameter	TT, 0.9V, 25°C	FF, 0.99V, -40°C	SS, 0.81V, 125°C			
Down Consumption	0.5108mW	0.9938mW	0.3432mW			
Fower Consumption	@320MHz	@320MHz	@320MHz			



## 4.2.3 Table of Comparison

Parameter	Prop	osed	[10]	[32]	
Process	40-nm	90-nm	90-nm	90-nm	
Core Area (µm×µm)	120×120	180×180	300×300	200×200	
Category	ADPLL	ADPLL	ADPLL	ADPLL	
Lock-in Time (cycles)	4.5	4.5	4	4	
Supply Voltage (V)	0.9	1.0	1.0	1.0	
Time Resolution	Time Resolution3.43ps		41ps@0.52V 6.6ps@1.0V	6.109ps	
Input Frequency (MHz)	Frequency MHz) 5		5	5~20	
Output Frequency (MHz)	129.8~1465	93~1428	40~160@0.52V 160~460@1.0V	80~1606	
Multiplication Factor		1~511	2~128	1~63	
Power Consumption	0.3749mW @0.9V, 129 MHz 0.981mW @0.9V, 1.47GHz 0.031mW @0.5V, 80MHz	0.2759mW @ 93MHz 1.6278mW @ 1428MHz 0.9045mW @ 600MHz	37µW @0.52V, 120MHz 0.92mW @1.0V, 600MHz	0.3037mW @80MHz 1.73mW @1606MHz	

Table 4.6: Performance Comparison Table with Prior Design.

Table 4.6 shows the comparison table with our prior researches. For fair comparison, we also implement the proposed ADPLL in TSMC 90-nm CMOS process. The proposed ADPLL has relatively fine DCO resolution and small chip area. Table 4.7 shows the comparison table with previous researches. Although [4] claims to lock-in in two clock cycles, it still has a large frequency error after two cycles. In addition, the frequency error comes from the quantization effects of the frequency counter.

		[2]	[26]	[1]	[6]	[5]	[4]
Parameter	Proposed	TCAS-II	ASSCC	JSSC	ICECS	ISCAS	TCAS-II
		'13	'12	'15	'14	'14	'10
Process	40-nm	28-nm	40-nm	40-nm LP	65-nm	90-nm	180-nm
Core Area	120-120	52-45	250-140	216-216	260-270	222,200	250,200
(µm×µm)	120×120	32×43	550×140	310×310	300×270	525×200	230×300
Category	ADPLL	ADPLL	ADPLL	Digital LC	ADPLL	ADPLL	ADPLL
				PLL			
Lock-in Time	4 5	<50 (1us)	42	40	45	<7	2
(cycles)		(1µ3)	12	10	10		
Supply	0.9	1.0	0.5	0.9	1.0	1.2	1.8
Voltage (V)							
Time	3.43ps	0.3~2.4ps	351ps	0.21fs	5fs	3.923ps	8.8ps
Resolution							@446MHz
Input							
Frequency	5	5		390	15	3~10	0.22~8
(MHz)							
Output			1	21400~251			
Frequency	129.8~1465	83~2000	<mark>10~</mark> 100	00	1500~2800	460~6117	223~446
(MHz)							
Multiplication	1~511	50	10~100	16	100~187	50~2000	45~128
Factor							
Frequency	0.43% @			0.6%			1%@
Error	Multiplication	N/A	N/A	@ 25GHz	N/A	N/A	Multiplication
	Factor=44						Factor>=45
	0.3749mW						
	@0.9V, 129 MHz		4.7μW				
Power	0.981mW	0.64mW	@10MHz	64mW	8.85mW	9.237mW	14.5mW
Consumption	@0.9V, 1.47GHz	@2GHz	0.045mW			@6GHz	@446MHz
	31µW		@100MHz				
	@0.5V, 80MHz						

Table 4.7: Performance Comparison Table.

# **Chapter 5**

# **Conclusion and Future Works**

## **5.1 Conclusion**

In this thesis, an all-digital phase-locked loop (ADPLL) with an improving frequency estimation algorithm is presented. The frequency estimation algorithm requires the period ratio information that is calculated from the cyclic counter. In addition, the target DCO control code can be calculated by the frequency finder within 4.5 cycles.

Although the cyclic counter only can calculate the period ratio into integer numbers, we propose a calibration method to reduce quantization error. The calibration method can not only estimate the period ratio into fixed-point numbers, but also optimize the hardware utilization as compare to previous design with a cyclic TDC. Therefore, the proposed ADPLL can achieve fast lock-in time in 4.5 cycles.

Besides, the proposed interpolator-based fine-tuning architecture effectively solves the non-monotonic response problem of the DCO at 0.9V supply voltage. In addition, the interpolator-based fine-tuning architecture also improves the accuracy of the frequency estimation algorithm.

Therefore, in order to minimize the power consumption and reduce the chip area, the test chip is implemented in TSMC 40-nm CMOS process.

## **5.2 Future Works**

In this thesis, there are some drawbacks in our ADPLL. The first issue is the DCO power consumption consumes most of the power consumption of the ADPLL. If we can reduce the power consumption of the DCO, we can minimize the ADPLL's total power consumption. Therefore, design a low-power DCO is required to further reduce the power consumption of the ADPLL.

There is another issue about frequency estimation algorithm. In section 1.2.4, we discuss the frequency estimation algorithm with and without the cyclic TDC. Although the cyclic TDC reduces the quantization error, the cyclic TDC cost large area. We assumed that the large area of the cyclic TDC is not concern. If we use the cyclic TDC and the proposed calibration method to calculate the period ratio, maybe we can further improve the accuracy of the initial target frequency.

Besides, there are some factors that may affect the estimation error in the frequency estimation algorithm such as jitter and duty cycle of the reference clock. If the reference clock duty cycle is not close to 50%, as we quantify the half of the reference clock, the quantization error may significantly increase. Therefore, if we quantify a clock period of the reference clock, the challenge of the duty cycle may be solved. However, the proposed frequency estimation algorithm should take at least 5 reference cycles to lock the target frequency.

Besides, as an ADPLL is operated at an extremely worse case, the reference clock jitter becomes large. In addition, the large jitter may significantly increase the estimation error. Therefore, after the frequency estimation algorithm, maybe we can increase the value of the step in binary search algorithm to reduce the lock-in time.

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